

G “ZLM Position” - Calibration Software

A number of standards authorities and institutions have issued standards and recommendations for the inspection of coordinate measuring machines and machine-tools.

The "Position" measuring program is designed for the inspection of coordinate measuring machines and machine-tools in accordance with the following standards,

- ISO 230
- VDI/DGQ 3441
- VDI/VDE 2617
- NMTBA

by means of position measurements and their statistical analysis. The VDI/VDE 2617 recommendation also covers straightness, squareness and angle measurements, for which other programs within the range of ZLM software are available.

The first part (G 1) of this chapter on the "Position" measuring program deals with the principles of the measurement and analysis procedures. The second part (G 2) describes the operation of the measurement program.

G 1 Principles of Measurement and Analysis

Objective of measurement in inspecting machine-tools: Assessment of the accuracy to which components can be machined

Objective of measurement in inspecting coordinate measuring machines: Assessment of the machine's measuring accuracy

Result of a measurement: Relevant standards define parameters and recommend graphs by which the systematic and random deviations from the ideal state of a machine can be assessed. The present program supplies these parameters and diagrams as results of measurements.

The standards and recommendations quoted above specify **identical measurement methods**. They differ mainly by their ways of calculating the parameters and presenting the results graphically.

G 1.1 Methods of measurement

Along a line corresponding to the path of a laser beam, the software moves the machine under test to a number of positions, each from both directions.

For the acquisition of measurement data, the following points should be minded:

- Establish at least one line parallel to each machine axis of interest, along which measurement positions can be moved to.
- Measurement positions should be distributed throughout the range of travel.

Further recommendations on selecting measurement positions are given by the standards quoted.

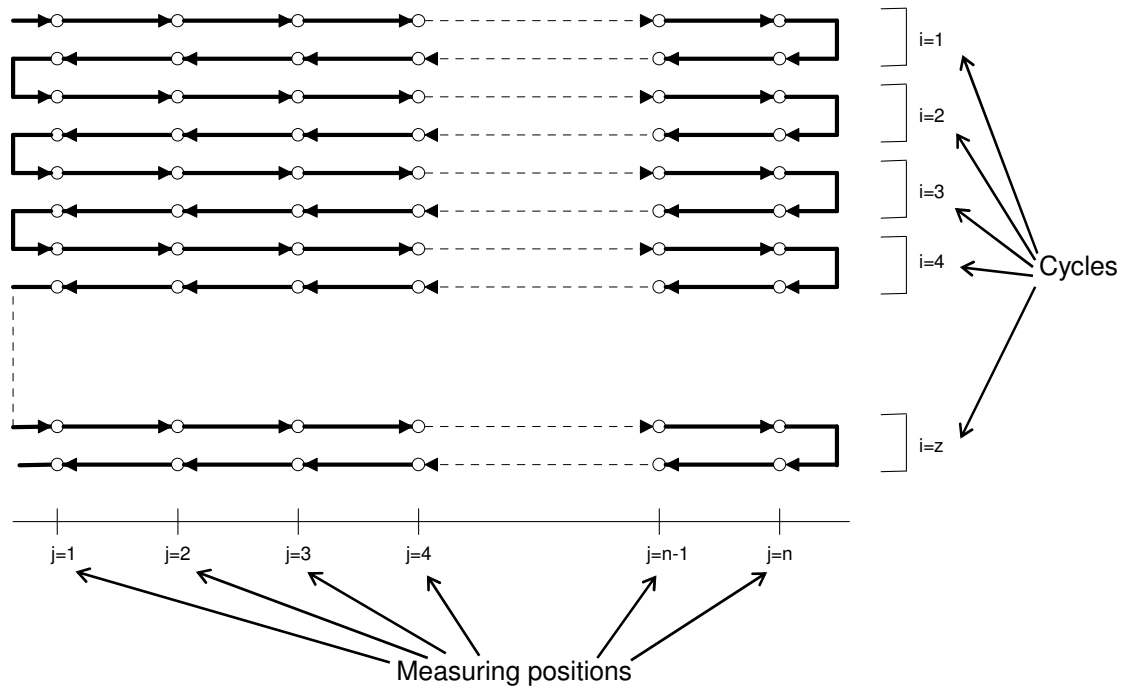
Standard	Minimum number, absolute	Minimum number per scale element	Equation for establishing nominal positions
ISO 230	5 (for measured lengths up to 1 m) 5 per metre (for measured lengths up to 2 m)	1	$P_j = N \cdot p \cdot r$ P_j - nominal position N - integer r - random decimal fraction p - greatest period
VDI/DGQ 3441	10 per metre + 1 (for measured lengths up to 2 m)	1	
VDI/VDE 2617	11	2	

G 1.2 Positioning methods

In order to yield statistical information on its positioning behaviour, the object under test must be moved to a number of positions several times. Among the positioning methods used in practice, the program supports the linear, unidirectional linear, oscillation (also called "pendulum-step") and quasi-pilgrim step ("quasi-pilger") methods.

G 1.2.1 Linear method

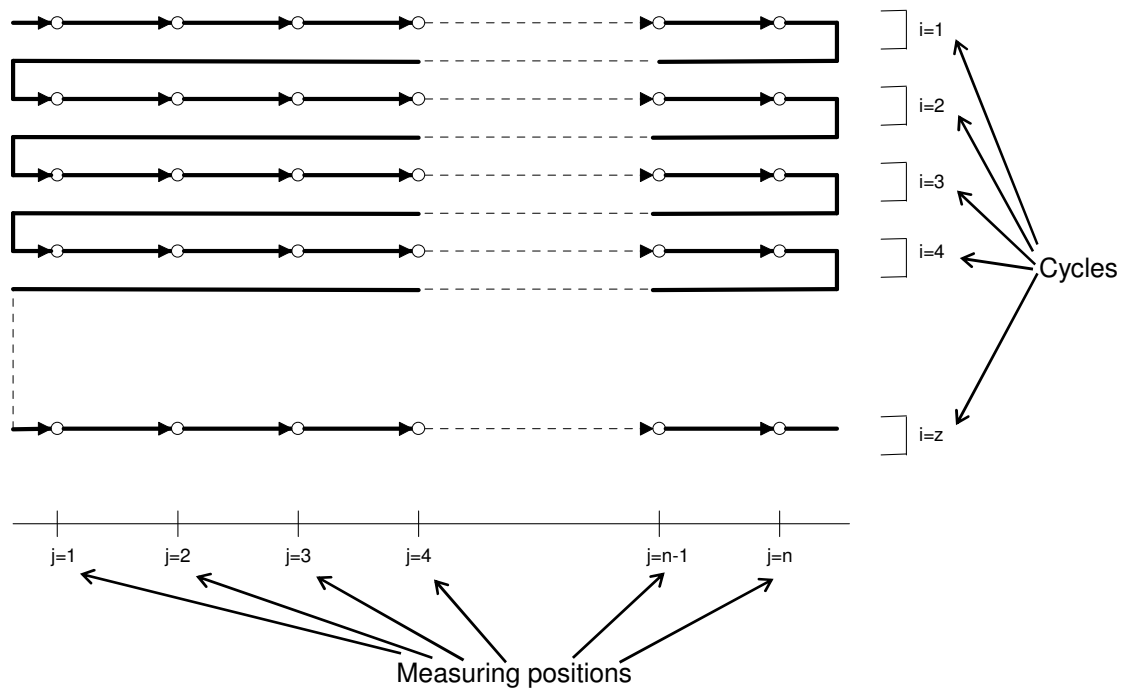
With the linear method, all positions are first travelled to in succession in the positive direction and then again in succession in the negative direction. The whole procedure is repeated several times (cycles).



In order to ensure that the first and last positions in each cycle are travelled to from the correct direction, it is necessary to provide an approach length at the start of the procedure, and a return loop at the end of each half-cycle.

This positioning method is easy to program. With great distances between positions, however, the total measurement takes considerable time. Greater temperature variations during that time will affect both the backlash error (reversal span) and the position spread (see section G 1.3).

G 1.2.2 Unidirectional linear method

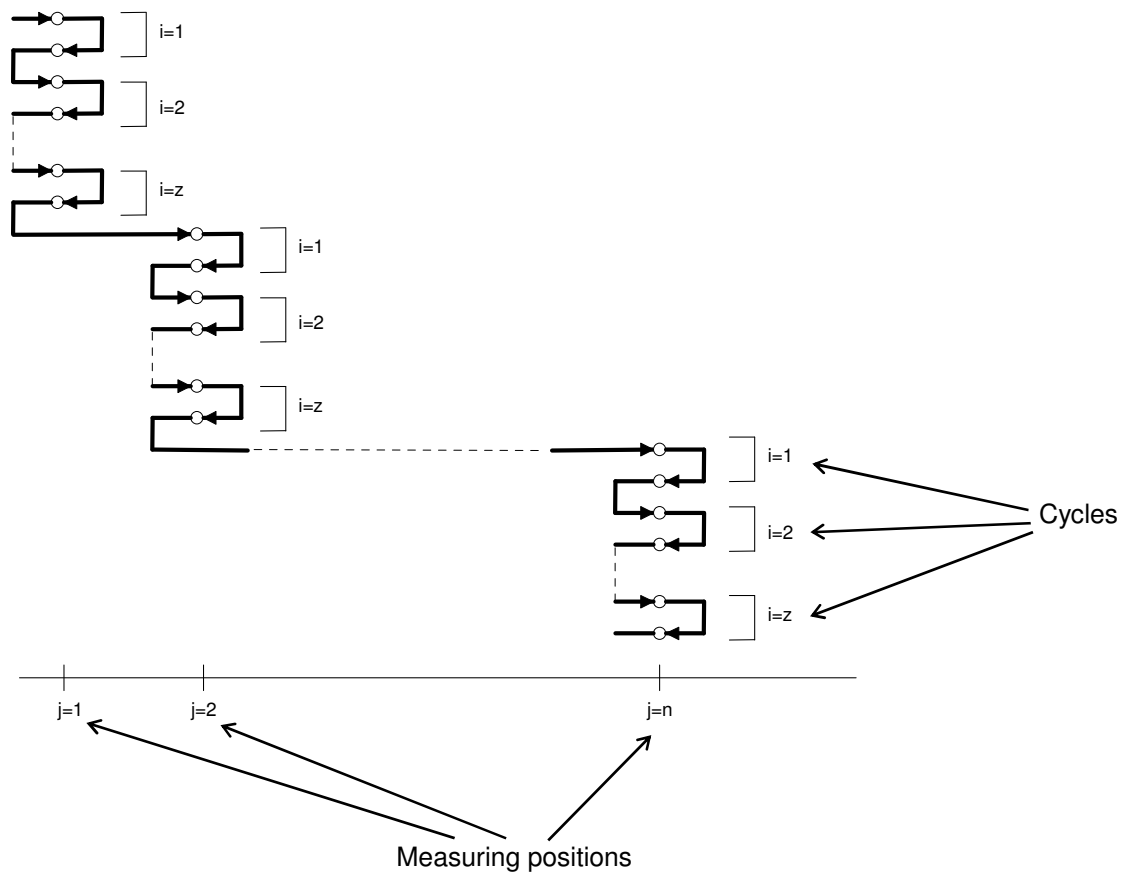


If it can be assumed that the differences between positioning in positive and positioning in negative directions are negligible (i.e. a small backlash error (reversal span)), the unidirectional linear method suggests itself.

In an extreme case one might also make a single-cycle rapid test.

Mind, however, that the standard analysis procedures issued by the standardization bodies (described in section G 1.3) do not provide for this positioning method.

G 1.2.3 Oscillation ("Pendulum-step") method

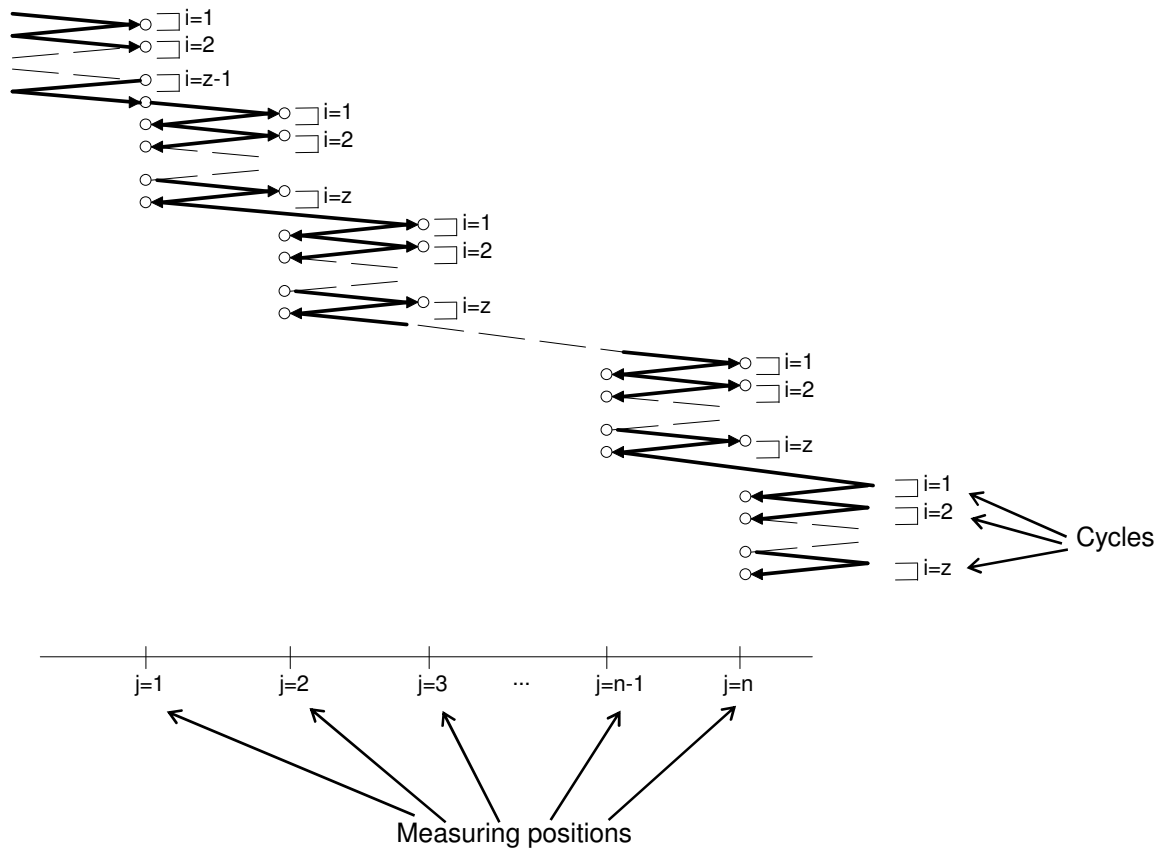


With this method, each measurement position is repeatedly travelled to, alternatingly from the positive and negative directions, before the measurement proceeds with the next position.

Of all the methods described, the Oscillation method involves the shortest total length of travel. This is of advantage especially where the positions are spaced far apart.

Great temperature variations during the measurement affect neither the backlash error (reversal span) nor the position spread (see sect. G 1.3). However, because of the long time passed between measuring the first and measuring the last position, thermal and other influences occurring during that time enter the measurement as systematic errors.

G 1.2.4 Quasi-pilgrim step ("Quasi-pilger") method



With this method, the first measurement position is travelled to several times in positive direction. Next, alternating travels are performed to the second position in positive direction and to the first position in negative direction. The pattern of alternating travels to the j^{th} and $(j+1)^{\text{th}}$ positions is continued until the last position has been travelled to repeatedly in the positive direction. Finally, the last position needs to be travelled to repeatedly in the negative direction.

Same as with the Oscillation method, great temperature variations during the measurement do not affect the backlash error (reversal span) nor the position spread, but enter the measurement as systematic errors.

G 1.3 Standard analysis procedures

The relevant standards and recommendations differ greatly in their procedures of computing the parameters and in their modes of presenting the result graphically.

What they all have in common is that they define a set of parameters that separately characterize

- systematic position deviations,
- random position deviations, and
- composite (systematic plus random) deviations.

These three kinds of parameters can also be obtained separately from the graphs established according to all the standards concerned.

Let the significance of the parameters be explained by the example of a machine-tool:

Systematic position deviations:

The standards concerned, except ISO 230, define a "**Position deviation**". With a certain quantity of like parts being machined on a machine-tool, the "Position deviation" indicates the average machining error to be expected for the parts.

The standards concerned, except for NMTBA, specify a "**Backlash**" (ISO) or "**Reversal span**" (the other standards). The "Backlash" or "Reversal span" indicates the average effect to be expected if in the machining process a position is travelled to from one position instead of the other.

Random position deviations:

The "**Position spread**" indicates the maximum differences to be expected in at least 99.5% of the machined parts. (As an exception, VDI/VDE 2617 specifies the position spread for coordinate measuring machines, computed for 95% of the reading errors to be expected.)

Composite position deviations:

The "**Position uncertainty**" indicates the machining error to be expected in a 99.5% yield, irrespective of the positioning direction.

The charts on the following pages show how the parameters and graphs are computed according to the different standards.

VDI/DGQ 3441	<p>z - Number of measuring cycles n - Number of positions i - Cycle number j - Position number</p>	<p>x_{ij} - Deviation (actual-nominal) at position j during cycle i ↑ - Positive travel direction ↓ - Negative travel direction</p>
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Diagram:

Average deviation: $\bar{x}_{j\uparrow} = \frac{1}{z} \sum_{i=1}^z x_{ij\uparrow}$ $\bar{x}_{j\downarrow} = \frac{1}{z} \sum_{i=1}^z x_{ij\downarrow}$ $\bar{x}_j = \frac{\bar{x}_{j\uparrow} + \bar{x}_{j\downarrow}}{2}$

Position spread: $P_{sj} = 3 \cdot \left(\sqrt{\frac{1}{z-1} \sum_{i=1}^z (x_{ij\uparrow} - \bar{x}_{j\uparrow})^2} + \sqrt{\frac{1}{z-1} \sum_{i=1}^z (x_{ij\downarrow} - \bar{x}_{j\downarrow})^2} \right)$

Reversal span: $U_j = |\bar{x}_{j\uparrow} - \bar{x}_{j\downarrow}|$

Deviation (micrometers)

The graph plots deviation in micrometers against target position in metres (0.0 to 1.0). It features several data series: a solid red line for the average deviation \bar{x}_j , dashed blue lines for the upper and lower bounds of the position spread $\bar{x}_{j\uparrow} + \frac{P_{sj}}{2}$ and $\bar{x}_{j\downarrow} - \frac{P_{sj}}{2}$, and dotted green lines for the reversal span U_j . Vertical arrows indicate the spread $P_{sj}/2$ and the reversal span $U_j/2$ at a specific target position of 0.6 metres.

Parameters:

Position spread: $P_{s\max} = \max[P_{sj}]_{j=1}^n$ $P_{s\mit} = \frac{1}{n} \sum_{j=1}^n P_{sj}$

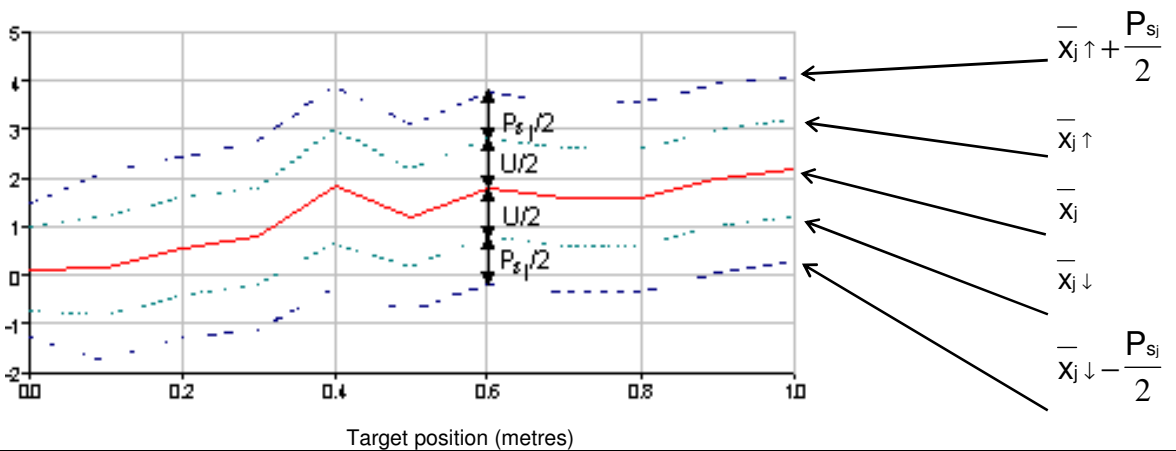
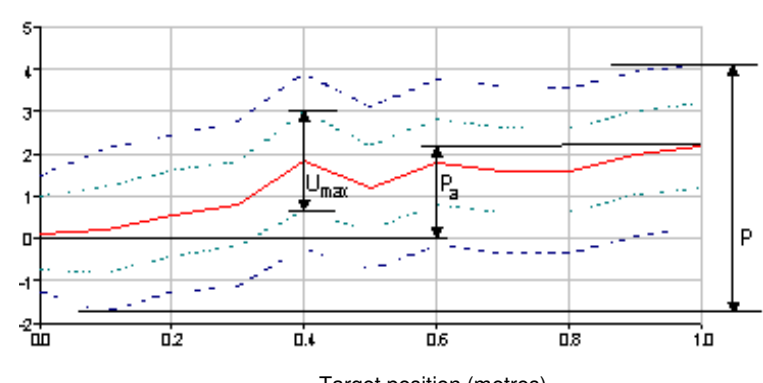
Reversal span: $U_{\max} = \max[U_j]_{j=1}^n$ $U_{\mit} = \frac{1}{n} \sum_{j=1}^n U_j$

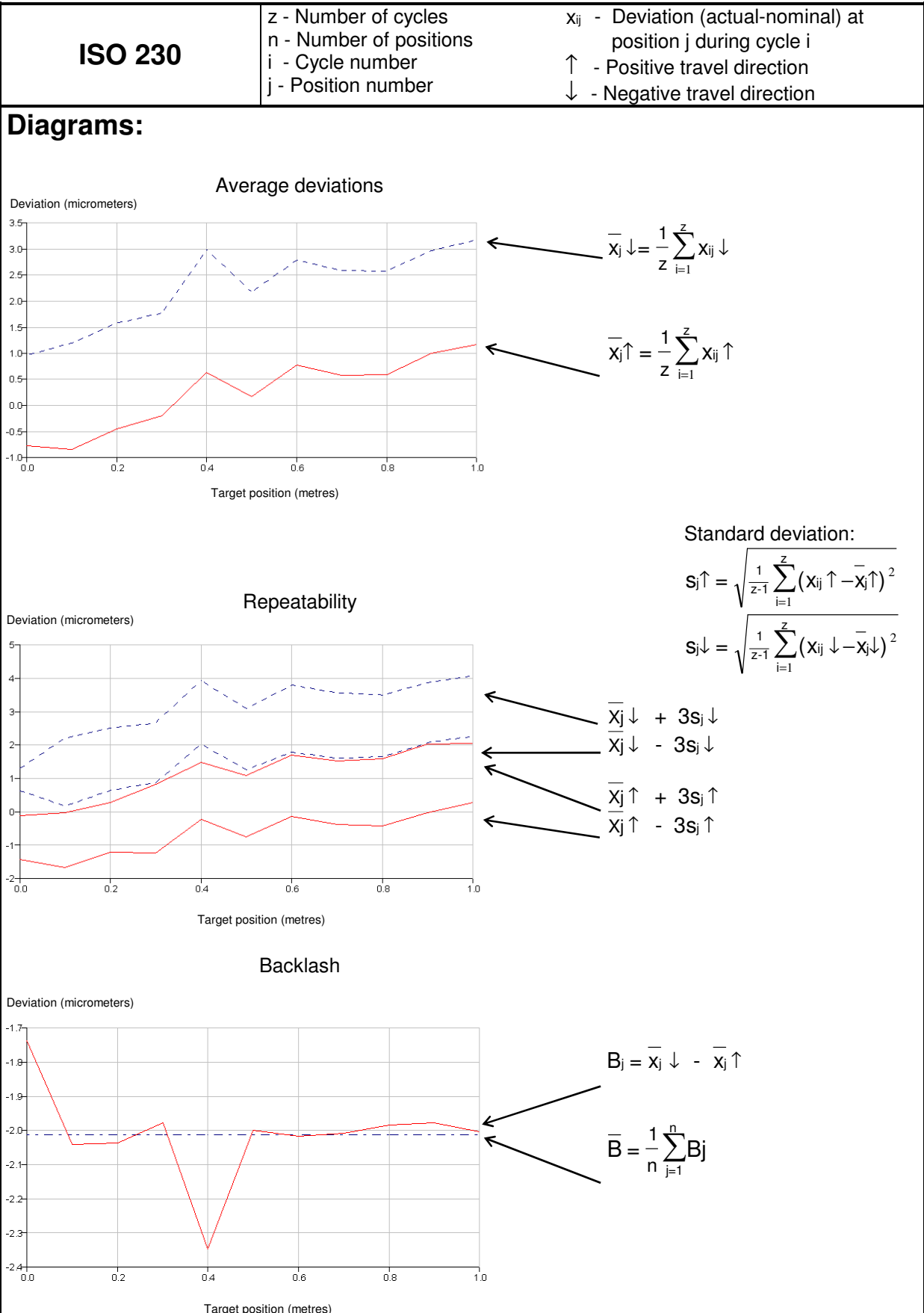
Position deviation: $P_a = \left| \max[\bar{x}_j]_{j=1}^n - \min[\bar{x}_j]_{j=1}^n \right|$

Position uncertainty: $P = \max \left[\bar{x}_j + \frac{1}{2}(U_j + P_{sj}) \right]_{j=1}^n - \min \left[\bar{x}_j - \frac{1}{2}(U_j + P_{sj}) \right]_{j=1}^n$

Deviation (micrometers)

This graph is similar to the one above but highlights overall statistical parameters. A vertical double-headed arrow labeled U_{\max} indicates the maximum reversal span across all positions. Another vertical double-headed arrow labeled P_a indicates the maximum position deviation. A large vertical double-headed arrow labeled P indicates the total position uncertainty across the entire range of target positions.

VDI/VDE 2617	<p>z - Number of cycles n - Number of positions i - Cycle number j - Position number</p>	<p>x_{ij} - Deviation (actual-nominal) at position j during cycle i ↑ - Positive travel direction ↓ - Negative travel direction</p>
Diagram:		
Average deviation:	$\bar{x}_{j\uparrow} = \frac{1}{z} \sum_{i=1}^z x_{ij\uparrow} \quad \bar{x}_{j\downarrow} = \frac{1}{z} \sum_{i=1}^z x_{ij\downarrow} \quad \bar{x}_j = \frac{\bar{x}_{j\uparrow} + \bar{x}_{j\downarrow}}{2}$	
Position spread:	$P_{sj} = 2 \cdot \left(\sqrt{\frac{1}{z-1} \sum_{i=1}^z (x_{ij\uparrow} - \bar{x}_{j\uparrow})^2} + \sqrt{\frac{1}{z-1} \sum_{i=1}^z (x_{ij\downarrow} - \bar{x}_{j\downarrow})^2} \right)$	
Reversal span:	$U_j = \bar{x}_{j\uparrow} - \bar{x}_{j\downarrow} $	
Deviation (micrometers)		
 <p>The graph plots deviation in micrometers (y-axis, -2 to 5) against target position in metres (x-axis, 0.0 to 1.0). It shows multiple data series: a solid red line for average deviation, dashed blue lines for position spread, and dotted green lines for reversal span. Vertical arrows indicate $P_{sj}/2$, $U/2$, and \bar{x}_j at a target position of 0.6. On the right, arrows point to the theoretical limits: $\bar{x}_{j\uparrow} + \frac{P_{sj}}{2}$, $\bar{x}_{j\uparrow}$, \bar{x}_j, $\bar{x}_{j\downarrow}$, and $\bar{x}_{j\downarrow} - \frac{P_{sj}}{2}$.</p>		
Parameters:		
Position spread	$P_{s\max} = \max[P_{sj}]_{j=1}^n \quad P_{s\mit\text{mit}} = \frac{1}{n} \sum_{j=1}^n P_{sj}$	
Reversal span	$U_{\max} = \max[U_j]_{j=1}^n \quad U_{\mit\text{mit}} = \frac{1}{n} \sum_{j=1}^n U_j$	
Position deviation	$P_a = \left \max[\bar{x}_j]_{j=1}^n - \min[\bar{x}_j]_{j=1}^n \right $	
Position uncertainty	$P = \max \left[\bar{x}_j + \frac{1}{2}(U_j + P_{sj}) \right]_{j=1}^n - \min \left[\bar{x}_j - \frac{1}{2}(U_j + P_{sj}) \right]_{j=1}^n$	
Deviation (micrometers)		
 <p>This graph is similar to the one above but highlights overall parameters. A vertical arrow labeled U_{\max} indicates the maximum reversal span. Another arrow labeled P_a indicates the maximum position deviation. A large vertical arrow labeled P indicates the total position uncertainty across the entire range.</p>		



ISO 230	z - Number of cycles	x_{ij} - Deviation (actual-nominal) at position j during cycle i
	n - Number of positions	↑ - Positive travel direction
	i - Cycle number	↓ - Negative travel direction
	j - Position number	

Parameters:

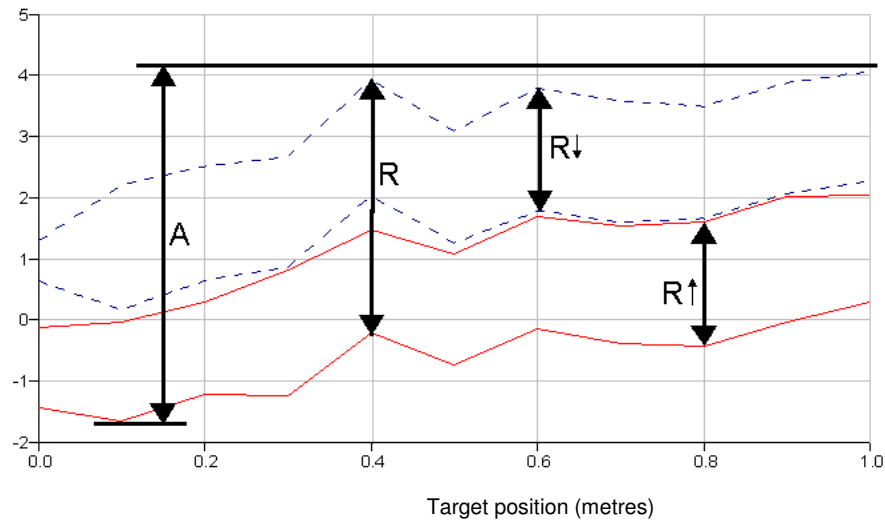
Position spread: $R = \max \left[\max \left[6s_j \uparrow, 6s_j \downarrow, 3s_j \uparrow + 3s_j \downarrow + |B_j| \right] \right]_{j=1}^n$

$R \uparrow = \max [6s_j \uparrow]_{j=1}^n$

$R \downarrow = \max [6s_j \downarrow]_{j=1}^n$

Position uncertainty $A = \max \left[\max \left[\bar{x}_j \uparrow + 3s_j \uparrow, \bar{x}_j \downarrow + 3s_j \downarrow \right] \right]_{j=1}^n - \min \left[\min \left[\bar{x}_j \uparrow - 3s_j \uparrow, \bar{x}_j \downarrow - 3s_j \downarrow \right] \right]_{j=1}^n$

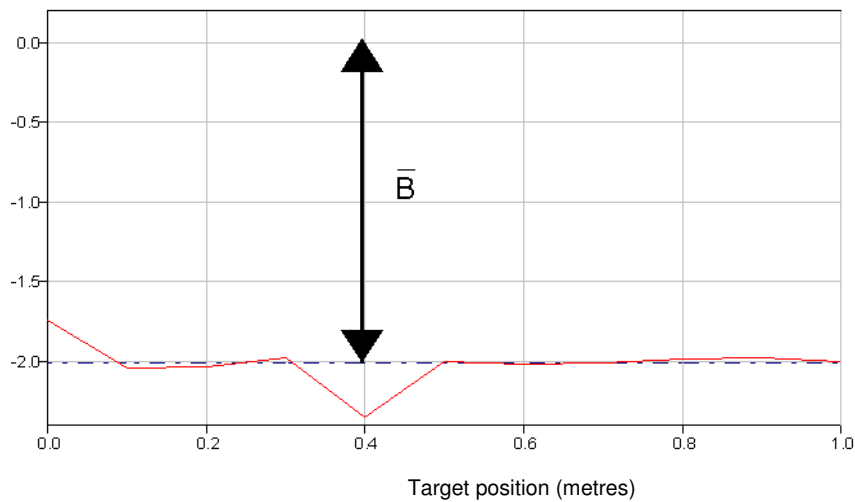
Deviation (micrometers)



Mean backlash

$$\bar{B} = \frac{1}{n} \sum_{j=1}^n (x_j \downarrow - x_j \uparrow)$$

Deviation (micrometers)



NMTBA	z - Number of cycles	x_{ij} - Deviation (actual-nominal) at position j during cycle i
	n - Number of positions	↑ - Positive travel direction
	i - Cycle number	↓ - Negative travel direction
	j - Position number	

Diagram:

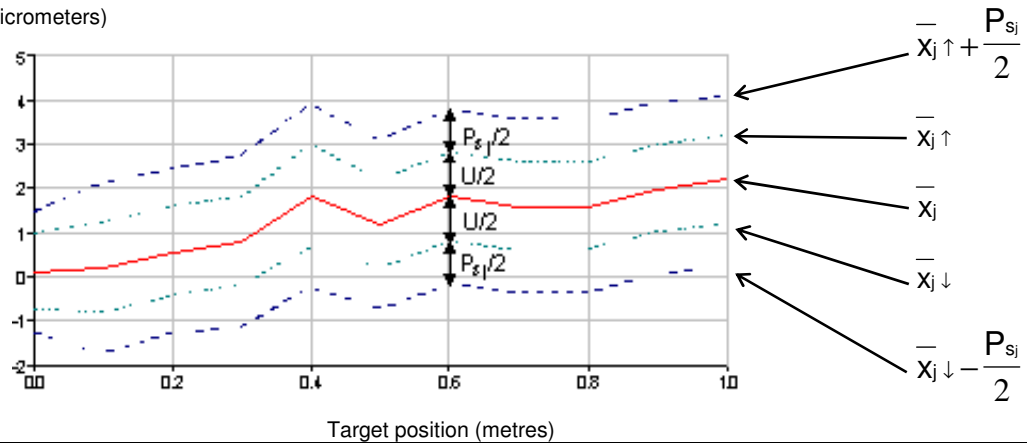
Average deviation:

$$\bar{X}_j = \frac{1}{2 \cdot z} \sum_{i=1}^z (X_{ij} \uparrow + X_{ij} \downarrow)$$

Position spread:

$$P_{sj} = 6 \cdot \sqrt{\frac{1}{2 \cdot z - 1} \sum_{i=1}^z \left\{ (X_{ij} \uparrow - \bar{X}_j)^2 + (X_{ij} \downarrow - \bar{X}_j)^2 \right\}}$$

Deviation (micrometers)



Target position (metres)

Parameters:

Position spread

$$P_{s \max} = \max [P_{sj}]_{j=1}^n \quad P_{s \text{ mit}} = \frac{1}{n} \sum_{j=1}^n P_{sj}$$

Offset

$$O = -\frac{1}{2} \cdot \left(\max \left[X_j + \frac{P_{sj}}{2} \right]_{j=1}^n + \min \left[X_j - \frac{P_{sj}}{2} \right]_{j=1}^n \right)$$

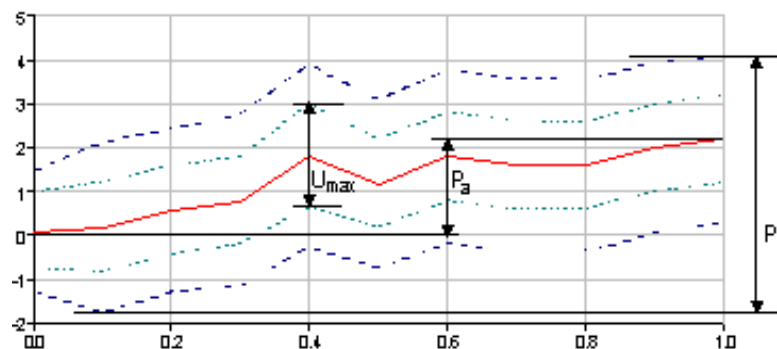
Position deviation

$$P_a = \left| \max [X_j]_{j=1}^n - \min [X_j]_{j=1}^n \right|$$

Position uncertainty

$$P = \max \left[X_j + \frac{P_{sj}}{2} \right]_{j=1}^n - \min \left[X_j - \frac{P_{sj}}{2} \right]_{j=1}^n$$

Deviation (micrometers)



Target position (metres)